

**Search Notes**

Application/Control No.

10/642,343

Examiner

Sara Addisu

Applicant(s)/Patent under  
Reexamination

GIESSLER ET AL.

Art Unit

3722

**SEARCHED**

Class	Subclass	Date	Examiner
407	53,54,61	11/16/2005	SA
408	230,227	11/16/2005	SA

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Dan Howell	6/7/2005	SA
Inventor name search	11/16/2005	SA
Consulted Hwei Su Payer about restricting claims 11-14 in class 76/108.6. Agreed	6/7/2005	SA
Consulted H. Payer about treverse to restricting claims 11-14. FIB (focused Ion Beam) is known as an alternative to grinding	11/17/2005	SA